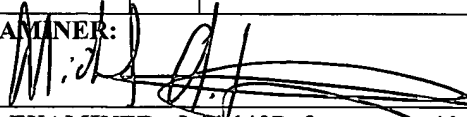


LIST OF PATENTS AND PUBLICATIONS										Attorney Docket:		Serial No.		
APPLICANT'S INFORMATION										101215-75		09/998,446		
DISCLOSURE STATEMENT (Form PTO-1449 Modified)										Applicant:				
										Jörg-Thomas Zettler et al.				
										Filing Date:		Group:		
										Nov. 30, 2001		TBA		
<b>U.S. PATENT DOCUMENTS</b>														
Examiner's Initial	Document Number	Date	Name	Class	Sub Class	Filing Date If appropriate								
MML	AA 5 4 0 3 4 3 3	4/1995	P. Morrison, et al.	156	626									
	AB													
	AC													
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	AF													
	AG													
	AH													
	AI													
	AJ													
	AK													
<b>FOREIGN PATENT DOCUMENTS</b>														
	Document Number	Date	Country	Class	Sub Class	Translation Yes No								
MML	AL 44 19 476	12/1994	Germany				✓							
	AM													
	AN													
	AO													
	AP													
<b>OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>														
MML	AR	Y. Li, et al. Simultaneous in situ Measurement of Substrate Temperature and Layer Thickness Using Diffuse Reflectance Spectroscopy (DRS) During Molecular Beam Epitaxy" Journal of Crystal Growth 175/176 (1997) pgs. 250-255												
MML	AS	K.Knorr, et al. "Real-time Monitoring of P-based Semiconductor Growth by Linear-optical Spectroscopy" Eighth International Conference on Indium Phosphide and Related Materials, 1996, IPRM '96, pgs. 590-593												
	AT													
EXAMINER: 										DATE CONSIDERED: Apr. 17, 2003				
<ul style="list-style-type: none"> <li>EXAMINER: Initial if Reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered, include copy of this form with next communication to applicant.</li> <li></li> </ul>														